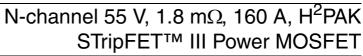


STH200N55F3-2



Preliminary data

Features

Туре	V _{DSS}	V _{DSS} R _{DS(on)} max	
STH200N55F3-2	55 V	< 2.6 m Ω	160 A

- 1. Current limited by package
- Ultra low on-resistance
- 100% avalanche tested

Application

Switching applications

Description

This STripFET[™] III Power MOSFET technology is among the latest improvements, which have been especially tailored to minimize on-state resistance providing superior switching performance.

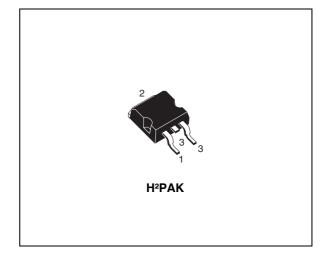


Figure 1. Internal schematic diagram

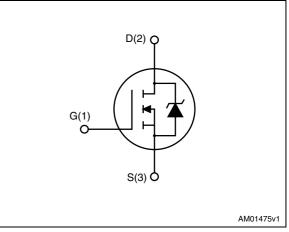


Table 1. Device summary

Order code	Marking	Package	Packaging
STH200N55F3-2	200N55F3	H ² PAK	Tape and reel

Doc ID 16085 Rev 1

www.st.com

This is preliminary information on a new product now in development or undergoing evaluation. Details are subject to change without notice.

Contents

1	Electrical ratings	3
2	Electrical characteristics	4
3	Test circuits	6
4	Package mechanical data	7
5	Revision history	10



1

Electrical ratings

Table 2. Absolute maximum ration

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage (V _{GS} = 0)	55	V
V _{GS}	Gate-source voltage	± 20	V
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25 °C	160	А
Ι _D	Drain current (continuous) at T _C = 100 °C	160	А
I _{DM} ⁽²⁾	Drain current (pulsed)	640	А
P _{TOT} ⁽³⁾	Total dissipation at $T_C = 25 \ ^{\circ}C$	300	W
	Derating factor	2.0	W/°C
E _{AS} ⁽⁴⁾	Single pulse avalanche energy	1.0	J
T _{stg} Storage temperature		55 to 175	J°
Тj	Operating junction temperature	-55 to 175	

1. Current limited by package

2. Pulse width limited by safe operating area

3. This value is rated according to Rthj-c

4. Starting Tj = 25 °C, I_D = 60 A, V_{DD} = 35 V

	Table 3.	Thermal data
--	----------	--------------

Symbol Parameter		Value	Unit
Rthj-case Thermal resistance junction-case max		0.5	°C/W
Rthj-pcb ⁽¹⁾ Thermal resistance junction-pcb max		35	°C/W

1. When mounted on 1 inch² FR-4 2 oz Cu



2 Electrical characteristics

(T_{case} = 25 °C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_{D} = 250 \ \mu A, \ V_{GS} = 0$	55			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	$V_{DS} =$ Max rating, $V_{DS} =$ Max rating, $T_c = 125 \ ^{\circ}C$			1 10	μΑ μΑ
I _{GSS}	Gate body leakage current (V _{DS} = 0)	V _{DS} = ± 20 V			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	2		4	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10 V, I _D = 60 A		1.8	2.6	mΩ

Table 4. On /off states

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 25 V, f = 1 MHz, V _{GS} =0	-	6800 1450 15	-	pF pF pF
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 44 \text{ V}, I_D = 120 \text{ A},$ $V_{GS} = 10 \text{ V}$ <i>Figure 3</i>	-	100 30 26	-	nC nC nC



	jj					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on delay time Rise time	$V_{DD} = 27.5 \text{ V}, \text{ I}_{D} = 60 \text{ A}$ $\text{R}_{\text{G}} = 4.7 \Omega, \text{ V}_{\text{GS}} = 10 \text{ V},$ $\textit{Figure 2}$	-	25 150	-	ns ns
t _{d(off)} t _f	Turn-off delay time Fall time	$V_{DD} = 27.5 \text{ V}, \text{ I}_{D} = 60 \text{ A}$ $R_{G} = 4.7 \Omega, V_{GS} = 10 \text{ V},$ <i>Figure 2</i>	-	110 50	-	ns ns

Table 6. Switching times

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SD} ⁽¹⁾	Source-drain current Source-drain current (pulsed)		-		160 640	A A
V _{SD} ⁽²⁾	Forward on voltage	$I_{SD} = 160 \text{ A}, V_{GS} = 0$	-		1.5	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 120 \text{ A,di/dt} = 100 \text{ A/}\mu\text{s}$ $V_{DD} = 35 \text{ V, } \text{T}_{j} = 150 ^{\circ}\text{C}$ Figure 7	-	60 110 3.5		ns nC A

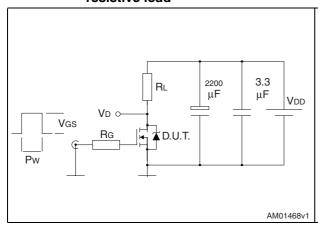
1. Pulse width limited by safe operating area

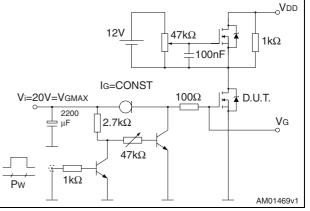
2. Pulsed: Pulse duration = 300 μ s, duty cycle 1.5%



3 Test circuits

Figure 2. Switching times test circuit for resistive load

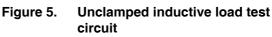


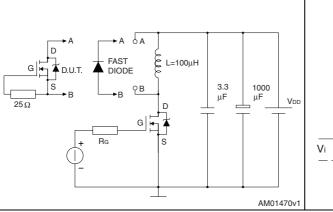


Gate charge test circuit

Figure 3.

Figure 4. Test circuit for inductive load F switching and diode recovery times





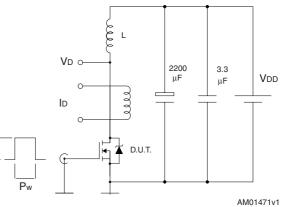
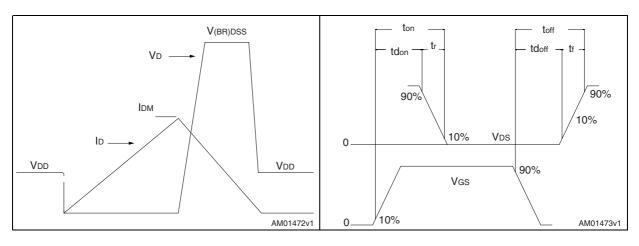


Figure 6. Unclamped inductive waveform

Figure 7. Switching time waveform





4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.



Dim		mm	
Dim.	Min.	Тур.	Max.
А	4.30		4.80
A1	0.03		0.20
С	1.17		1.37
е	4.98		5.18
E	0.50		0.90
F	0.78		0.85
Н	10.00		10.40
H1	7.171		7.971
L	15.30	-	15.80
L1	1.27		1.40
L2	4.93		5.23
L3	7.45		7.85
L4	1.5		1.7
М	2.6		2.9
R	0.20		0.60
V	0°		8°

 Table 8.
 H²PAK 2 leads mechanical data



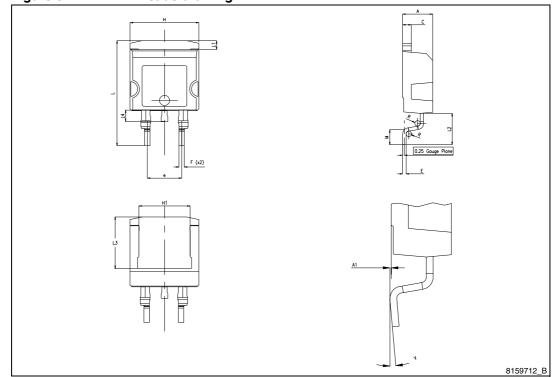
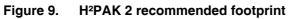
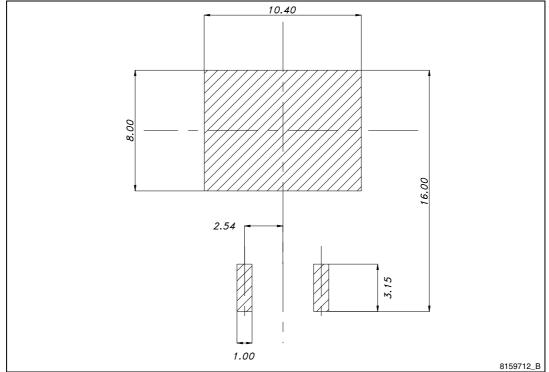


Figure 8. H²PAK 2 leads drawing







5 Revision history

Table 9.Document revision history

Date	Revision	Changes
30-Jul-2009	1	First release.



Please Read Carefully:

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

UNLESS EXPRESSLY APPROVED IN WRITING BY AN AUTHORIZED ST REPRESENTATIVE, ST PRODUCTS ARE NOT RECOMMENDED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE. ST PRODUCTS WHICH ARE NOT SPECIFIED AS "AUTOMOTIVE GRADE" MAY ONLY BE USED IN AUTOMOTIVE APPLICATIONS AT USER'S OWN RISK.

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

© 2009 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan -Malaysia - Malta - Morocco - Philippines - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com



Doc ID 16085 Rev 1

11/11